

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TEH, JIN TEIK	
		Examiner Chirag R. Patel	Art Unit 2141	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0049842	04-2002	Huetsch et al.	709/225
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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